

## SANYO Semiconductors DATA SHEET

P-Channel Silicon MOSFET

# **3LP04MH** — General-Purpose Switching Device **Applications**

#### **Features**

• 1.5V drive.

#### **Specifications**

#### Absolute Maximum Ratings at Ta=25°C

Parameter	Symbol	Conditions	Ratings	Unit
Drain-to-Source Voltage	VDSS		-30	V
Gate-to-Source Voltage	VGSS		±10	V
Drain Current (DC)	ID		-200	mA
Drain Current (Pulse)	IDP	PW≤10μs, duty cycle≤1%	-800	mA
Allowable Power Dissipation	PD	Mounted on a ceramic board (900mm <sup>2</sup> X0.8mm)	0.6	W
Channel Temperature	Tch		150	°C
Storage Temperature	Tstg		-55 to +150	°C

#### Electrical Characteristics at Ta=25°C

Parameter	Symbol	Conditions	Ratings			1.1-14
			min	typ	max	Unit
Drain-to-Source Breakdown Voltage	V(BR)DSS	ID=-1mA, VGS=0V	-30			V
Zero-Gate Voltage Drain Current	IDSS	V <sub>DS</sub> =-30V, V <sub>GS</sub> =0V			-1	μΑ
Gate-to-Source Leakage Current	IGSS	V <sub>GS</sub> =±8V, V <sub>DS</sub> =0V			±10	μΑ
Cutoff Voltage	VGS(off)	V <sub>DS</sub> =-10V, I <sub>D</sub> =-100μA	-0.4		-1.4	V
Forward Transfer Admittance	yfs	V <sub>DS</sub> =-10V, I <sub>D</sub> =-100mA	190	320		mS
Static Drain-to-Source On-State Resistance	R <sub>DS</sub> (on)1	ID=-100mA, VGS=-4V		1.8	2.4	Ω
	RDS(on)2	ID=-50mA, VGS=-2.5V		2.4	3.4	Ω
	R <sub>DS</sub> (on)3	ID=-10mA, VGS=-1.5V		4.5	9.0	Ω
Input Capacitance	Ciss	V <sub>DS</sub> =-10V, f=1MHz		35		pF
Output Capacitance	Coss	VDS=-10V, f=1MHz		7.2		pF
Reverse Transfer Capacitance	Crss	V <sub>DS</sub> =-10V, f=1MHz		2.1		pF
Turn-ON Delay Time	t <sub>d</sub> (on)	See specified Test Circuit.		75		ns
Rise Time	tr	See specified Test Circuit.		170		ns
Turn-OFF Delay Time	t <sub>d</sub> (off)	See specified Test Circuit.		550		ns
Fall Time	tf	See specified Test Circuit.		350		ns

Marking: QD Continued on next page.

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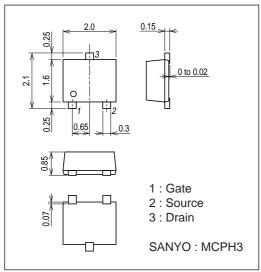
#### 3LP04MH

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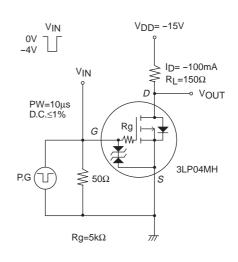
Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	Onic
Total Gate Charge	Qg	V <sub>DS</sub> =-10V, V <sub>GS</sub> =-4V, I <sub>D</sub> =-200mA		0.58		nC
Gate-to-Source Charge	Qgs	V <sub>DS</sub> =-10V, V <sub>GS</sub> =-4V, I <sub>D</sub> =-200mA		0.17		nC
Gate-to-Drain "Miller" Charge	Qgd	V <sub>DS</sub> =-10V, V <sub>GS</sub> =-4V, I <sub>D</sub> =-200mA		0.12		nC
Diode Forward Voltage	VSD	IS=-200mA, VGS=0V		-0.89	-1.2	V

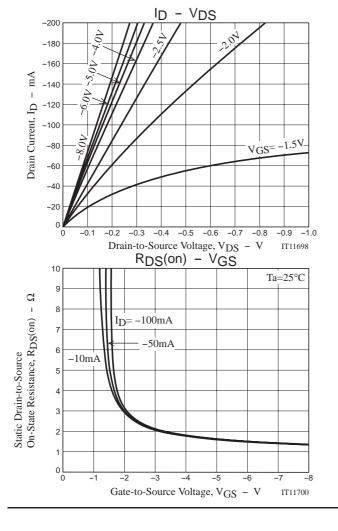
### **Package Dimensions**

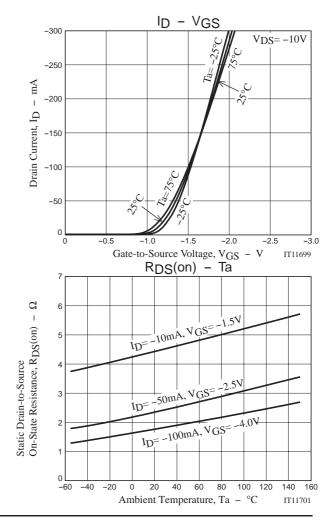
unit : mm (typ) 7019A-003



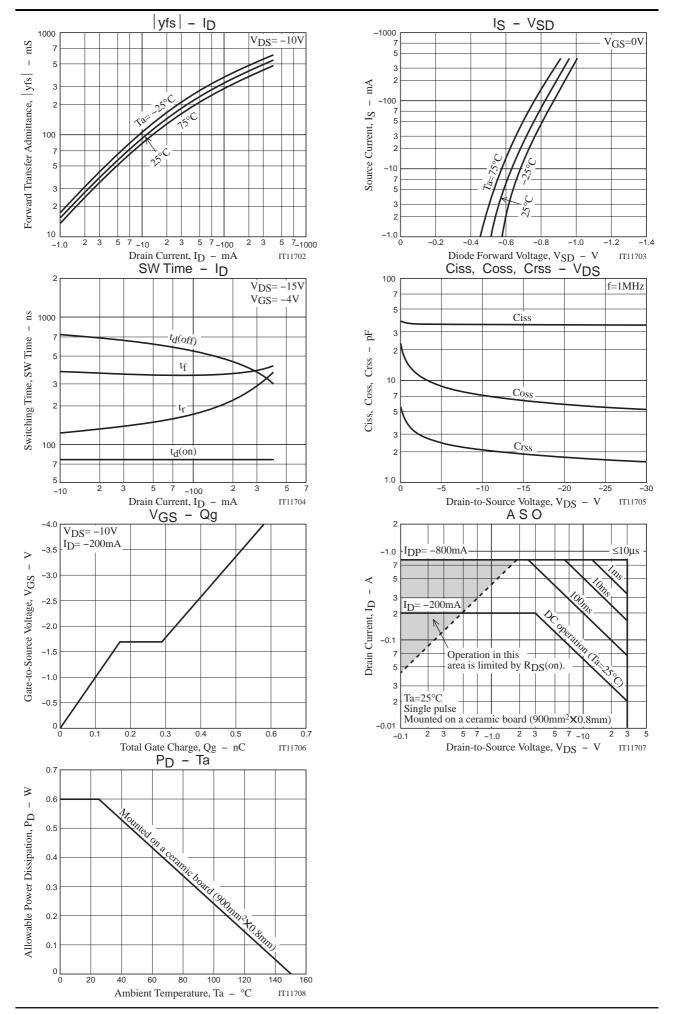
### **Switching Time Test Circuit**







#### 3LP04MH



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Note on usage: Since the 3LP04MH is a MOSFET product, please avoid using this device in the vicinity of highly charged objects.

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